



PATENT

-1-

THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of

Abdurrahman Sezginer, et al.

Application No.: 10/613,378

Filed: July 3, 2003

For: OVERLAY METROLOGY METHOD
AND APPARATUS USING MORE
THAN ONE GRATING PER
MEASUREMENT DIRECTION

Confirmation No.: 7200

Group Art Unit: 2877

Examiner: Gordon J. Stock, Jr.

**RESPONSE TO OFFICE ACTION
MAILED JUNE 7, 2005**

353 Sacramento St., Suite 2200
San Francisco, CA 94111
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M/S AMENDMENT
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited
with the United States Postal Service as First Class Mail in an
envelope, addressed to: Commissioner for Patents, P.O.
Box 1450, Alexandria, VA 22313-1450 on August 23, 2005.
STALLMAN & POLLOCK LLP

Dated: 08/23/2005

By:

Georgia K. Stith
Georgia K. Stith

Sir:

In response to the Office Action mailed June 7, 2005, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 4 of this paper.

Amendments to the Drawings begin on page 6 of this paper and include an attached replacement sheet.

Remarks/Arguments begin on page 7 of this paper.

Atty Docket No.: TTI-32410